PROCEEDINGS OF SPIE

X-Ray Nanoimaging: Instruments and Methods VII

Yong S. Chu Barry Lai Editors

6 August 2025 San Diego, California, United States

Sponsored and Published by SPIE

Volume 13622

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Please use the following format to cite material from these proceedings: Author(s), "Title of Paper," in X-Ray Nanoimaging: Instruments and Methods VII, edited by Yong S. Chu, Barry Lai, Proc. of SPIE 13622, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510691520

ISBN: 9781510691537 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA

Telephone +1 360 676 3290 (Pacific Time)

SPIE.ora

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